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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Kazuhito YASUDA, et al.

SERIAL NO.: NEW U.S. PCT APPLICATION

FILED: HEREWITH

INTERNATIONAL APPLICATION NO.: PCT/JP04/17891 INTERNATIONAL FILING DATE: November 24, 2004

FOR: SEMICONDUCTOR RADIATION DETECTOR AND PROCESS FOR PRODUCING THE

**SAME** 

## REQUEST FOR PRIORITY UNDER 35 U.S.C. 119 AND THE INTERNATIONAL CONVENTION

Commissioner for Patents Alexandria, Virginia 22313

Sir:

In the matter of the above-identified application for patent, notice is hereby given that the applicant claims as priority:

COUNTRY

**APPLICATION NO** 

**DAY/MONTH/YEAR** 

Japan

2003-397978

27 November 2003

Certified copies of the corresponding Convention application(s) were submitted to the International Bureau in PCT Application No. PCT/JP04/17891. Receipt of the certified copy(s) by the International Bureau in a timely manner under PCT Rule 17.1(a) has been acknowledged as evidenced by the attached PCT/IB/304.

Respectfully submitted, OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

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